



FQD7N10L / FQU7N10L

100V LOGIC N-Channel MOSFET

General Description

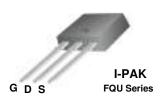
These N-Channel enhancement mode power field effect transistors are produced using Fairchild's proprietary, planar stripe, DMOS technology.

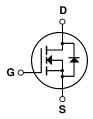
This advanced technology is especially tailored to minimize on-state resistance, provide superior switching performance, and withstand high energy pulse in the avalanche and commutation modes. These devices are well suited for low voltage applications such as high efficiency switching DC/DC converters, and DC motor control.

Features

- 5.8A, 100V, $R_{DS(on)} = 0.35\Omega @V_{GS} = 10 V$
- Low gate charge (typical 4.6 nC)
- · Low Crss (typical 12 pF)
- Fast switching
- · 100% avalanche tested
- · Improved dv/dt capability
- Low level gate drive requirments allowing direct operation from logic drives







Absolute Maximum Ratings T_C = 25°C unless otherwise noted

Symbol	Parameter		FQD7N10L / FQU7N10L	Units	
V_{DSS}	Drain-Source Voltage		100	V	
I _D	Drain Current - Continuous (T _C = 25°C	C)	5.8	Α	
	- Continuous (T _C = 100°	°C)	3.67	Α	
I _{DM}	Drain Current - Pulsed	(Note 1)	23.2	Α	
V _{GSS}	Gate-Source Voltage		± 20	V	
E _{AS}	Single Pulsed Avalanche Energy	(Note 2)	50	mJ	
I _{AR}	Avalanche Current	(Note 1)	5.8	Α	
E _{AR}	Repetitive Avalanche Energy	(Note 1)	2.5	mJ	
dv/dt	Peak Diode Recovery dv/dt	(Note 3)	6.0	V/ns	
P_{D}	Power Dissipation (T _A = 25°C) *		2.5	W	
	Power Dissipation (T _C = 25°C)		25	W	
	- Derate above 25°C		0.2	W/°C	
T _J , T _{STG}	Operating and Storage Temperature Range		-55 to +150	°C	
T _L	Maximum lead temperature for soldering purposes, 1/8" from case for 5 seconds		300	°C	

Thermal Characteristics

Symbol	Parameter	Тур	Max	Units
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case		5.0	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient *		50	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient		110	°C/W

* When mounted on the minimum pad size recommended (PCB Mount)

Symbol	Parameter	Test Conditions		Min	Тур	Max	Units
Off Cha	aracteristics						
BV _{DSS}	Drain-Source Breakdown Voltage	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$		100			V
ΔBV _{DSS} / ΔT _J	Breakdown Voltage Temperature Coefficient	$I_D = 250 \mu A$, Referenced to 25°C			0.1		V/°C
I _{DSS}	Zero Gate Voltage Drain Current	V _{DS} = 100 V, V _{GS} = 0 V				1	μΑ
		V _{DS} = 80 V, T _C = 125°C				10	μА
I _{GSSF}	Gate-Body Leakage Current, Forward	$V_{GS} = 20 \text{ V}, V_{DS} = 0 \text{ V}$				100	nA
I _{GSSR}	Gate-Body Leakage Current, Reverse	$V_{GS} = -20 \text{ V}, V_{DS} = 0 \text{ V}$				-100	nA
On Cha	aracteristics						
V _{GS(th)}	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_{D} = 250 \mu\text{A}$		1.0		2.0	V
R _{DS(on)}	Static Drain-Source	V _{GS} = 10 V, I _D = 2.9 A			0.275	0.35	-
	On-Resistance	$V_{GS} = 5 \text{ V}, I_D = 2.9 \text{ A}$			0.300	0.38	Ω
9 _{FS}	Forward Transconductance	$V_{DS} = 30 \text{ V}, I_{D} = 2.9 \text{ A}$	(Note 4)	-	4.6		S
C _{oss}	Output Capacitance Reverse Transfer Capacitance	$V_{DS} = 25 \text{ V}, V_{GS} = 0 \text{ V},$ f = 1.0 MHz			55 12	72 15	pF pF
C _{rss}] I = 1.0 IVID2					
Switchi	ing Characteristics						
$t_{d(on)}$	Turn-On Delay Time	$V_{DD} = 50 \text{ V}, I_D = 7.3 \text{ A},$ $R_G = 25 \Omega$		-	9	30	ns
t _r	Turn-On Rise Time				100	210	ns
$t_{d(off)}$	Turn-Off Delay Time	<u> </u>			17	45	ns
t _f	Turn-Off Fall Time		(Note 4, 5)	-	50	110	ns
Q_g	Total Gate Charge	$V_{DS} = 80 \text{ V}, I_{D} = 7.3 \text{ A}, $ $V_{GS} = 5 \text{ V}$			4.6	6.0	nC
Q _{gs}	Gate-Source Charge			-	1.0		nC
Q_{gd}	Gate-Drain Charge		(Note 4, 5)		2.6		nC
Drain-S	Source Diode Characteristics at	nd Maximum Ratings	S				
I _S	Maximum Continuous Drain-Source Diode Forward Current					5.8	Α
I _{SM}	Maximum Pulsed Drain-Source Diode Forward Current		ı		23.2	Α	
	Drain-Source Diode Forward Voltage	V _{GS} = 0 V, I _S = 5.8 A		ŀ		1.5	V
V_{SD}	- rame country - results and restauge						
V _{SD}	Reverse Recovery Time	$V_{GS} = 0 \text{ V}, I_S = 7.3 \text{ A},$			70		ns

- Notes:
 1. Repetitive Rating : Pulse width limited by maximum junction temperature 2. L = 2.23mH, I_{AS} = 5.8A, V_{DD} = 25V, R_G = 25 Ω, Starting T_J = 25°C 3. I_{SD} ≤ 7.3A, di/dt ≤ 300A/μs, V_{DD} ≤ BV_{DSS}, Starting T_J = 25°C 4. Pulse Test : Pulse width ≤ 300μs, Duty cycle ≤ 2% 5. Essentially independent of operating temperature

Typical Characteristics

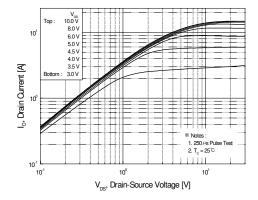


Figure 1. On-Region Characteristics

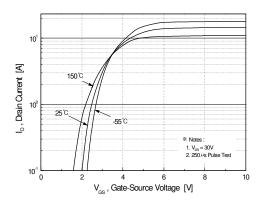


Figure 2. Transfer Characteristics

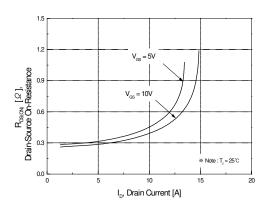


Figure 3. On-Resistance Variation vs. Drain Current and Gate Voltage

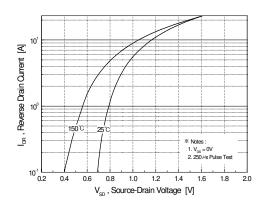


Figure 4. Body Diode Forward Voltage Variation vs. Source Current and Temperature

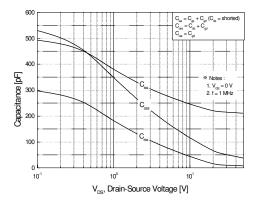


Figure 5. Capacitance Characteristics

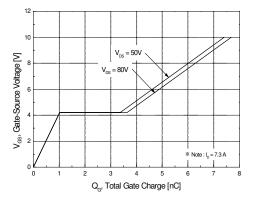
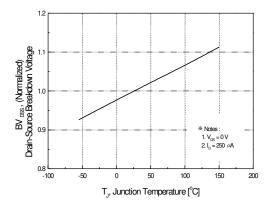


Figure 6. Gate Charge Characteristics

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Typical Characteristics (Continued)



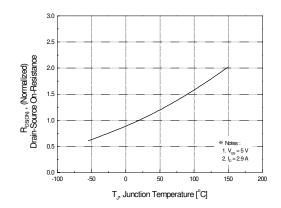
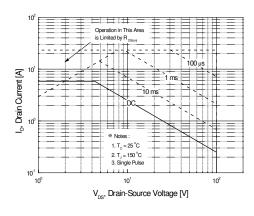


Figure 7. Breakdown Voltage Variation vs. Temperature

Figure 8. On-Resistance Variation vs. Temperature



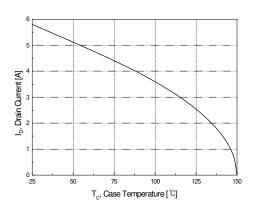


Figure 9. Maximum Safe Operating Area

Figure 10. Maximum Drain Current vs. Case Temperature

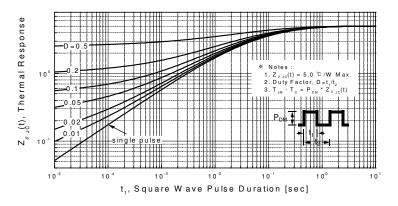
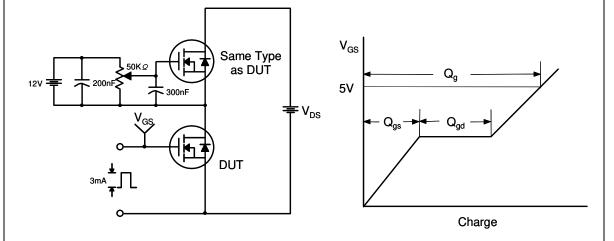


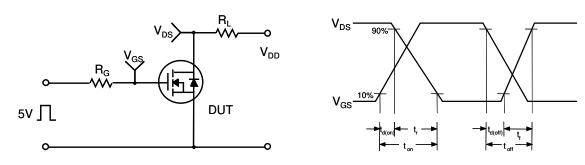
Figure 11. Transient Thermal Response Curve

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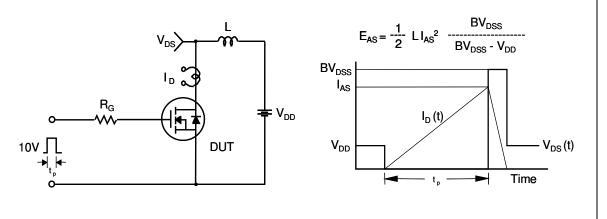
Gate Charge Test Circuit & Waveform



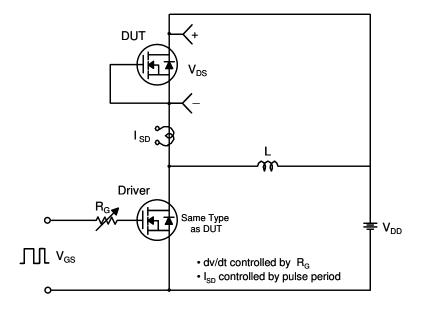
Resistive Switching Test Circuit & Waveforms

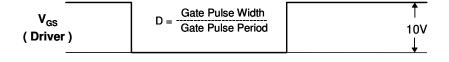


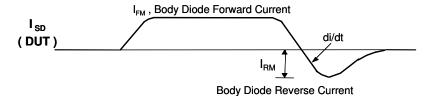
Unclamped Inductive Switching Test Circuit & Waveforms



Peak Diode Recovery dv/dt Test Circuit & Waveforms







V_{DS}
(DUT)

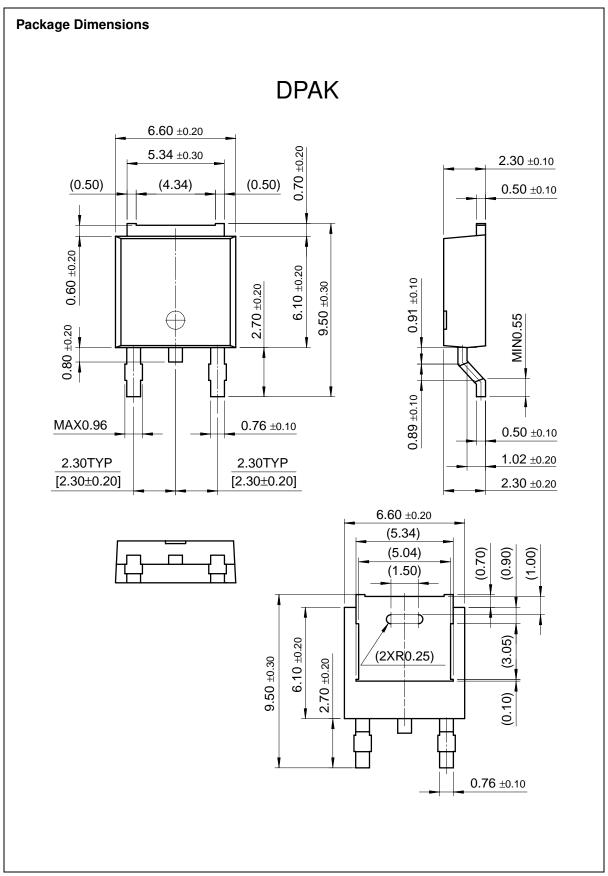
Body Diode Recovery dv/dt

V_{DD}

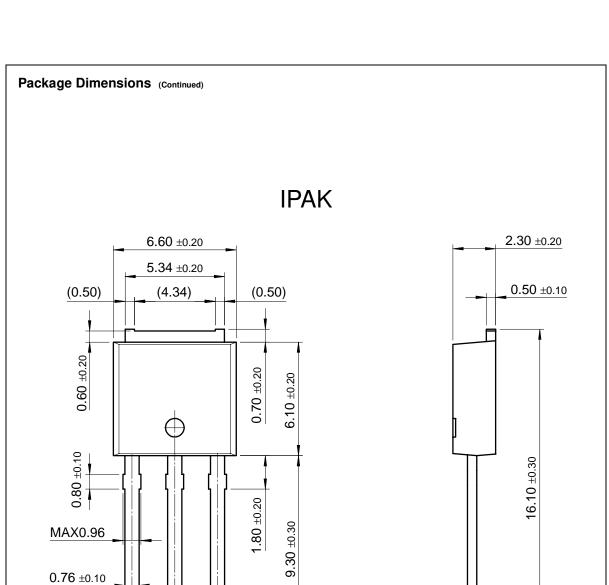
Body Diode

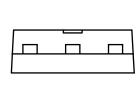
Forward Voltage Drop

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 0.50 ± 0.10





2.30TYP

[2.30±0.20]

2.30TYP

[2.30±0.20]

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